Se	earch Notes	

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
09/855,971	OMACHI, TAKAO	
Examiner	Art Unit	
Jade O. Laye	2617	

	SEARCHED		
Class	Subclass	Date	Examiner
725	34	8/1/2005	JL
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INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
received search from Scott Beliveau	8/2/2005	JL
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